

ISO 25178 - Roughness (S-L)

S-filter (λ_s): Gaussian, 2.5 μm

F-operation: None

L-filter (λ_c): Gaussian, 0.8 mm

Height parameters

Sq 11 nm

Sa 8.8 nm

Spatial parameters

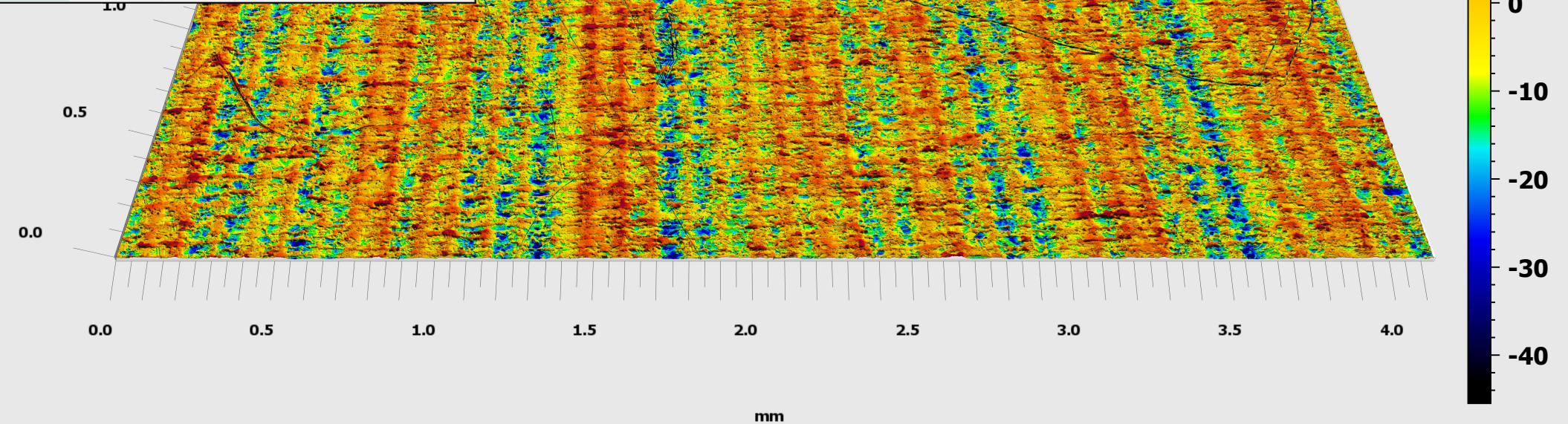
Sal 0.028 mm

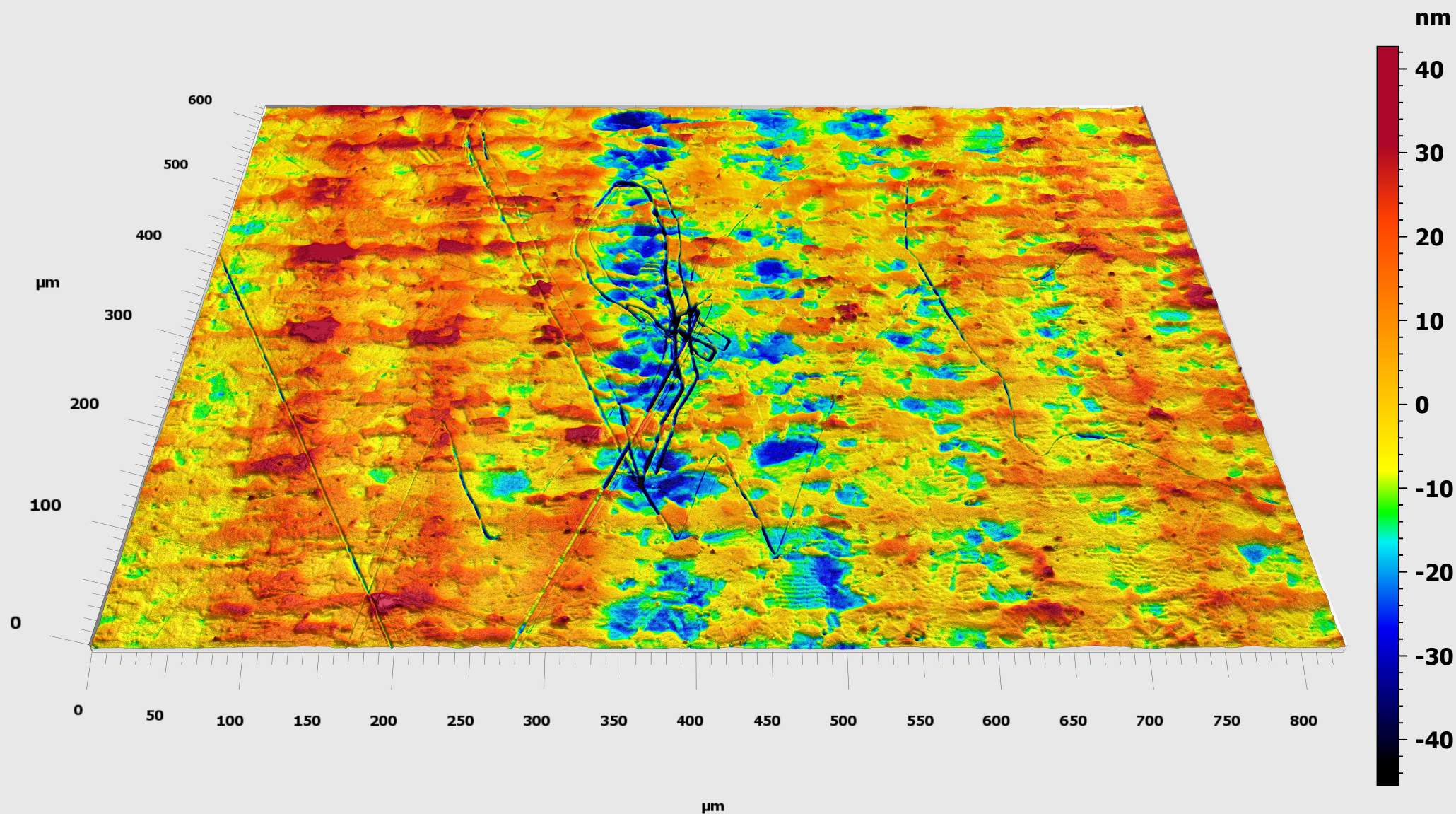
Functional parameters (stratified surfaces)

Sk 28 nm

Spk 12 nm

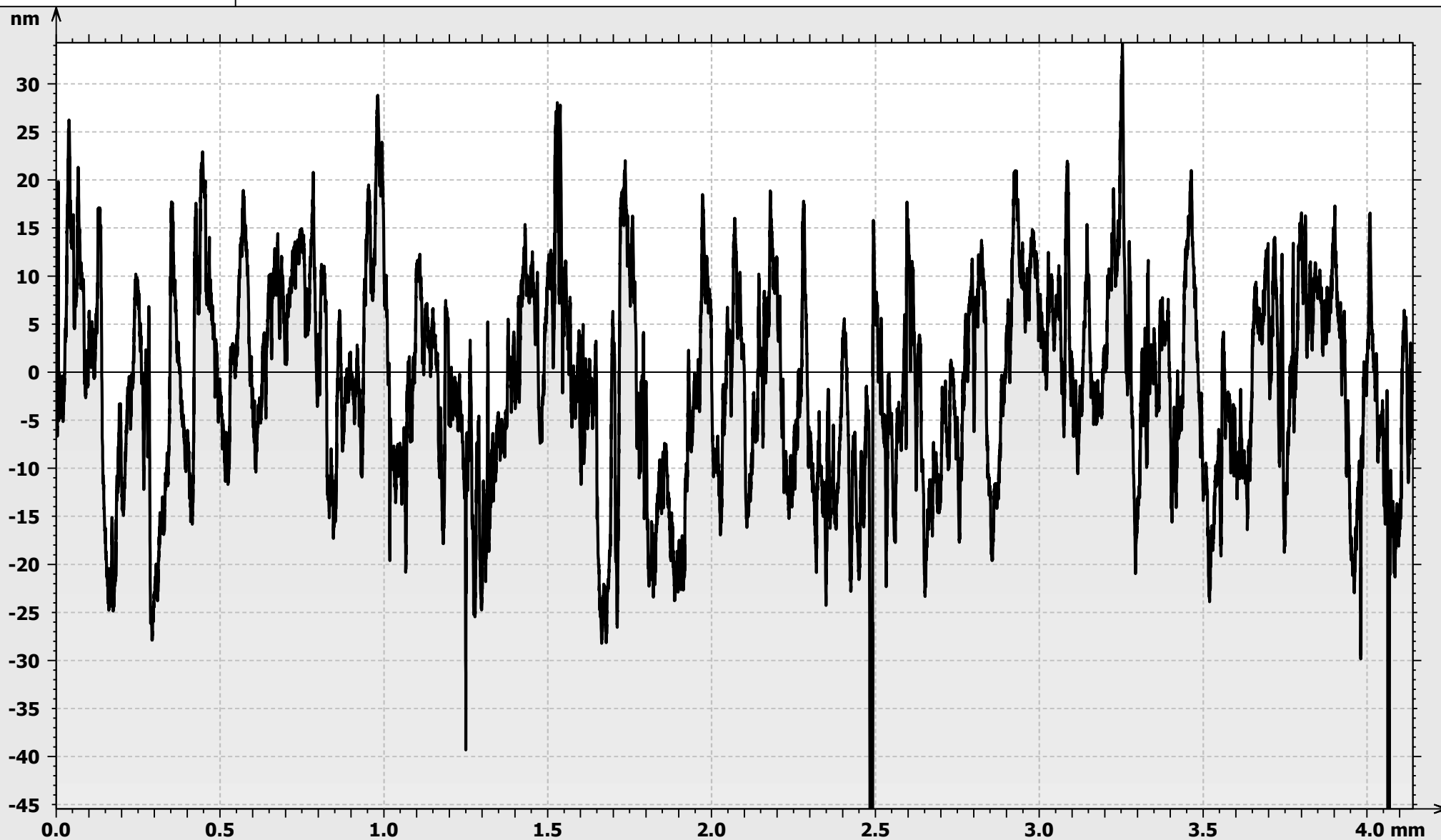
Svk 10 nm

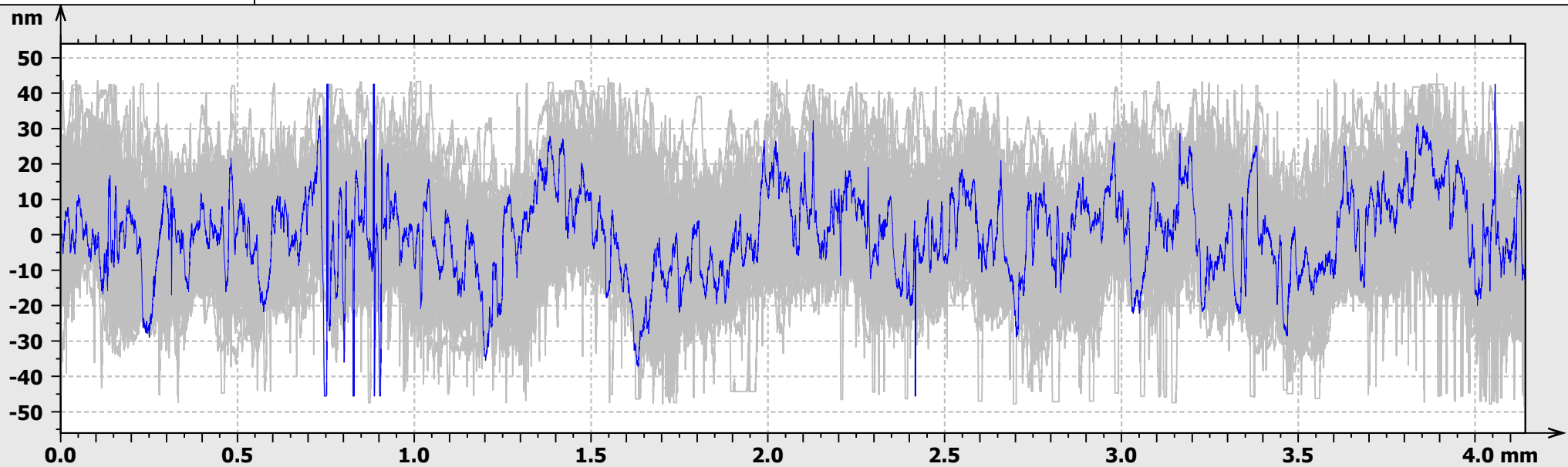






Parameters	Value	Unit
Sk	31	nm
Spk	13	nm
Svk	11	nm





Context	Mean	Std dev	Min	Max
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ISO 21920-Main - Roughness (S-L)

S-filter (λ_s): Gaussian, 2.5 μm

F-operation: None

L-filter (λ_c): Gaussian, 0.8 mm

Evaluation length: All λ_c (5)

Height parameters

Rq	nm	10	0.60	9.0	12
Rz	nm	58	4.6	48	71
Ra	nm	8.3	0.49	7.1	9.6

Spatial parameters

Ral	mm	$s = 0.2$	0.029	0.0031	0.022	0.039
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